

Notice of References Cited	Application/Control No. 10/709,932	Applicant(s)/Patent Under Reexamination OVERLINE, EUGENE	
	Examiner Wen-Ying P. Chen	Art Unit 2871	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,905,477	05-1999	Kuwayama et al.	345/7
	B	US-			
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	D	US-			
	E	US-			
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	I	US-			
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N	JP 2000142170 A	05-2000	Japan	KO et al.	B60K 35/00
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NON-PATENT DOCUMENTS

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	U	Machine-translated copy of JP 2000-142170A
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Wen-Ying P. Chen Sept. 21, 2005